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U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10008408	FILING DATE 11/13/2001	CLASS 714	SUBCLASS 738	GAU 2133	EXAMINER KERLERO S
<b>**APPLICANTS:</b> Purtell Michael; Yamoto Hiroaki; RSD					
<b>**CONTINUING DATA VERIFIED:</b> NONE JC 4/2/04					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> NONE JC 4/2/04					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO	
Verified and Acknowledged Examiners's initials		JC 4/2/04		ADTST.037AUS	
TITLE : Event based test system having improved semiconductor characterization map					
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)					

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	
		Print Claim for O.G.	
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
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